## Notice of References Cited

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Examiner

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Art Unit
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## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-6,347,372	02-2002	Takashima et al.	713/2
*	В	US-6,948,094 B2	09-2005	Schultz et al.	714/15
*	С	US-6,021,475 A	02-2000	Nguyen et al.	711/156
*	D	US-6,038,633 A	03-2000	Tavallaei, Siamak	710/262
*	E	US-6,065,121 A	05-2000	Hobson et al.	713/300
*	F	US-5,966,304 A	10-1999	Cook et al.	700/82
*	G	US-6,363,493 B1	03-2002	Williams, Emrys J.	714/1
*	Н	US-6,393,582 B1	05-2002	Klecka et al.	714/11
*	ı	US-6,449,250 B1	09-2002	Otani et al.	370/219
*	J	US-6,574,748 B1	06-2003	Andress et al.	714/11
*	Κ	US-6,725,396 B2	04-2004	Ahrens et al.	714/10
*	L	US-6,839,866 B2	01-2005	Lerman, Kenneth	714/13
*	М	US-6,012,151	01-2000	Mano, Kosei	714/11

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q	•				
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	x	

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